

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/555,586	GAN ET AL.	
Examiner	Art Unit	
Bin Shen	1657	

SEARCHED				
Class	Subclass	Date	Examiner	
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
PubMed-see printout.	8/20/2007	BS	
Inventor name searched.	8/20/2007	BS	
Priority document checked.	8/20/2007	BS	
SEQ search: NA.	8/20/2007`	BS	